

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/650,661	MORIWAKI ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
	Khanh V. Nguyen	2817

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Search History Printout		11/05/05	NKV